

## ABSTRACT OF THE DISCLOSURE

By executing internal verification block instructions in a semiconductor device having a function verification capability, internal verification blocks (11-1,..., and 11-n) supply optional input data items to corresponding target verification blocks (12-1,..., and 12-n) at optional timings, and operation verification for the target verification blocks (12-1,..., and 12-n) is performed.

11-1, ..., 11-n